

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/046,710	KUWAYAMA ET AL.	
Examiner	Chau N Nguyen	Art Unit	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0050385	05-2002	Murakami et al.	174/74.00R
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

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